VLSI Testing PA1 Report

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1. Testcase result

circuit	number of	number	number of	number of	number of	fault
number	test vector	of	total faults	detected	undetected	coverage
	pairs	gates		faults	faults	
C499	68	554	2390	2277	113	95.27%
C1355	63	554	2726	1702	1024	62.44%
C6288	42	4800	17376	17109	267	98.46%
C7552	289	5679	19456	19144	312	98.40%

2. Code explanation

a. In the TODO of fault detection, set the **detect** flag of a fault to be true if the output of fault-free circuit and faulty circuit are different.

```
for (i = 0; i < num_of_fault; i++) {
  if ((w->wire_value2 & Mask[i]) != (w->wire_value1 & Mask[i]))
    simulated_fault_list[i]->detect = TRUE;
}
```

In the TODO of fault injection, set the corresponding bits of wire_value2 to zeros or ones depending on the fault type.

```
if (fault == STUCK0)
  faulty_wire->wire_value2 &= ~(3 << (bit_position << 1));
else if (fault == STUCK1)
  faulty_wire->wire_value2 |= (3 << (bit_position << 1));</pre>
```

3. Speed up technique

For faster parallel simulation, we can use a 64-bit variable (i.e. **long long** or **unsigned long long**) to store the simulation pattern.

```
struct WIRE {
    ...
    long long wire_value1;
    long long wire_value2;
    long long fault_flag;
    ...
};
```

We also need to change other variables and function prototypes to **unsigned long long**. Some constant also need to be expanded to 64 bits.

The improvement is not very obvious because the test cases are too small. The following table shows the runtime (in seconds) of the golden program (golden_atpg), my program before improvement (atpg) and my program after improvement (atpg_improve).

circuit number	golden_atpg	atpg	atpg_improve	
C17	0.002	0.002	0.002	
C499	0.020	0.018	0.017	
C1355	0.021	0.018	0.014	
C6288	0.149	0.130	0.107	
C7552	0.416	0.364	0.327	